

Laboratori Nazionali di Frascati

LNF-87/67

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C. Quaresima and M. Capozi:
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ON Si (III) 2x1 IN THE RANGE 140-300°K**

Estratto da:
SIF - Conf. Proc. "Synchrotron Radiation at Frascati" Vol. 5, 221 (1986)

TEMPERATURE-DEPENDENT ADSORPTION OF ORGANIC MOLECULES
ON Si(III)2x1 IN THE RANGE 140-300°K

M.N.Piancastelli, R.Zanoni

Dip. di Chimica, Università "La Sapienza" di Roma, Roma, Italy

M.K.Kelly, D.Kilday, G.Margaritondo

Department of Physics and Synchrotron Radiation Center,
University of Wisconsin, Madison, Wisconsin 53706, USA

P.Perfetti, C.Quaresima and M.Capozi

Istituto di Struttura della Materia del CNR, and Progetto per
l'Utilizzazione della Luce di Sincrotrone, 00044 Frascati, Italy

In the general frame of a systematic investigation on the interaction of organic molecules with semiconductor surfaces, we studied the temperature-dependent adsorption of thiophene, C_4H_4S , and pyridine, C_5H_5N on Si(III)2x1 by synchrotron-radiation-excited photoemission, using the vacuum ultraviolet beam line of the "PULS" facility at the Frascati National Laboratories of the INFN.

Recent HREELS measurements⁽¹⁾ revealed 2 different adsorption states of thiophene on Si(III)2x1 at low temperatures, depending on exposure: i) direct interaction of thiophene with Si atoms (1-20L); ii) formation of a multilayer of thiophene on the surface (30-200L). At $T > 270^{\circ}\text{K}$ thiophene decomposes loosing the S atom while the C_4H_4 residual chain directly links with one or more Si atoms in cyclic structures. Present photoemission measurements have confirmed and completed the above reported results.

We report in Fig. 1 a Si(III)2x1 spectrum taken at 150°K (1a) and spectrum of thiophene adsorbed on Si(III)2x1 in the following conditions: 1b) $T=150^{\circ}\text{K}$, exposure 5L; 1c) $T=150^{\circ}\text{K}$, 200L; 1d) $T=300^{\circ}\text{K}$, 50L. 5 structures are evident in Fig. 1b) at -2.6, -6.1, -10.8, -15.6 and -19.4 eV from the top of the VB. With reference to Fig. 1a) and to the gas-phase thiophene spectrum⁽²⁾ we can correlate the peak at -2.6 with Si electronic states, while the remaining 4 peaks are related to thiophene MO. The most noticeable difference between Fig. 1b) and 1c) resides in a diminished relative intensity of the first peak with respect to the remaining ones, according with the hypothetical formation of a multilayer of thiophene on the surface. In Fig. 1d) there is a clear reversal in the relative intensity of thiophene-related peaks and Si-related structures, with respect to previous spectra.

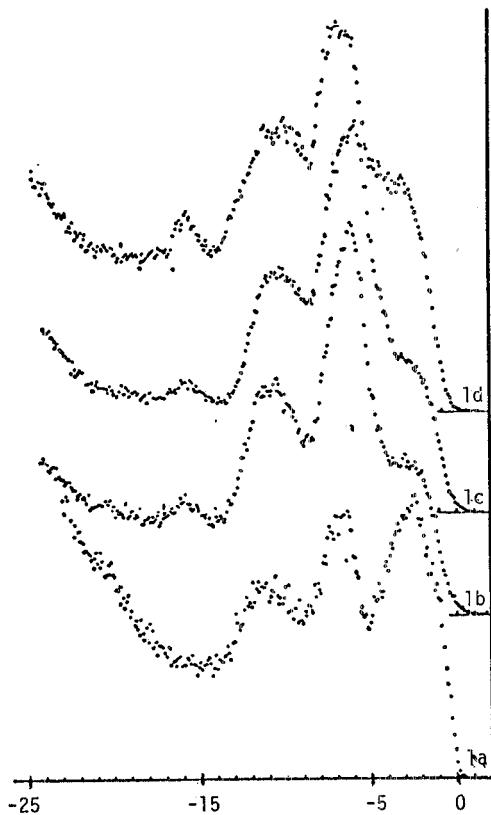


Fig. 1 - Photoemission spectra ($h\nu=40$ eV) of clean and C_4H_4S -adsorbed Si(III)2x1. (See text).

Preliminary results on pyridine adsorption at 150°K confirmed⁽³⁾ the existence, at low T^(4,5), of an adsorption state different from that already found at room T.

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